

Optimizing Plasma-Assisted Semiconductor Chip Manufacturing

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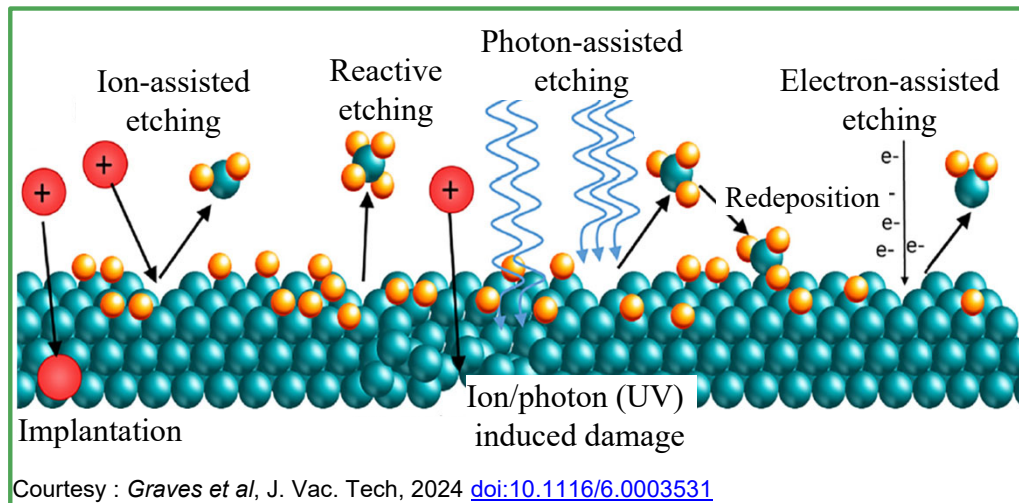
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HPC4EI Workshop
25th February, 2026



Need “digital twin” for optimizing complex chip fabrication

Current chip fabrication process design involves trial & error approach - costly and time consuming



Courtesy : Graves et al, J. Vac. Tech, 2024 [doi:10.1116/6.0003531](https://doi.org/10.1116/6.0003531)

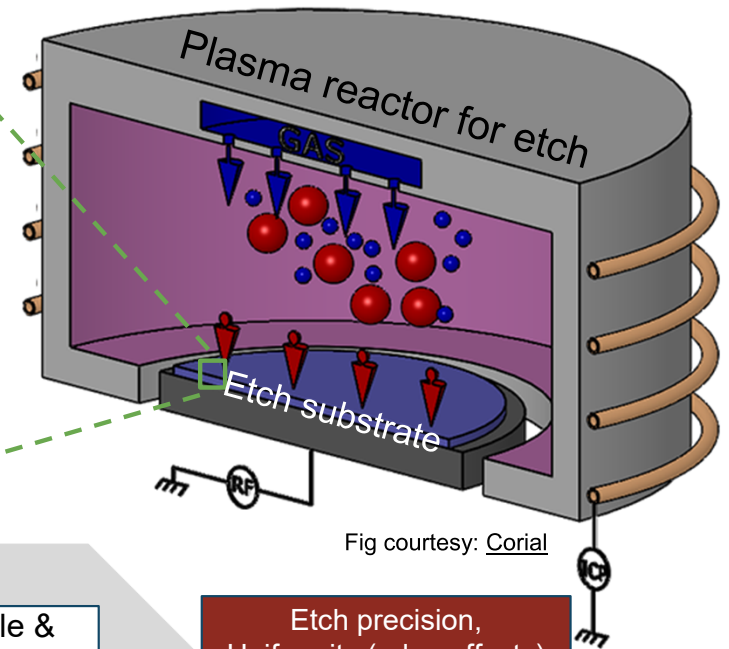
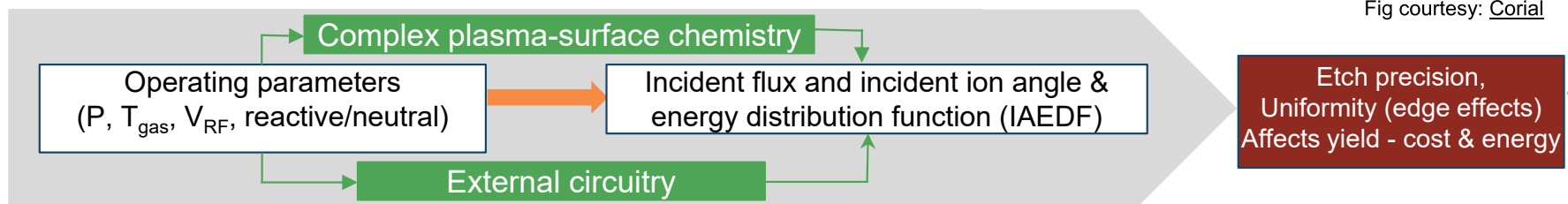


Fig courtesy: Corial

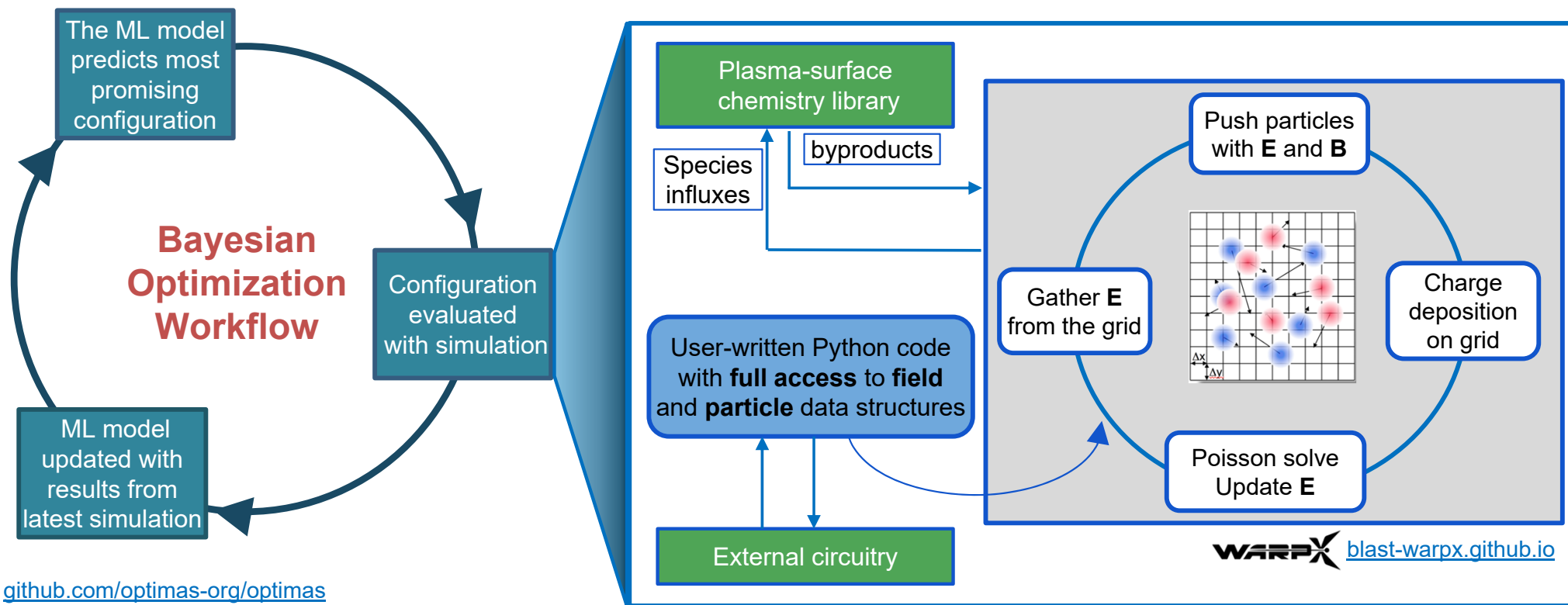


Need for a virtual fabrication tool - “digital twin”:

- (a) process design and optimization for high precision, high-yield
- (b) investigations of complex near-surface physics

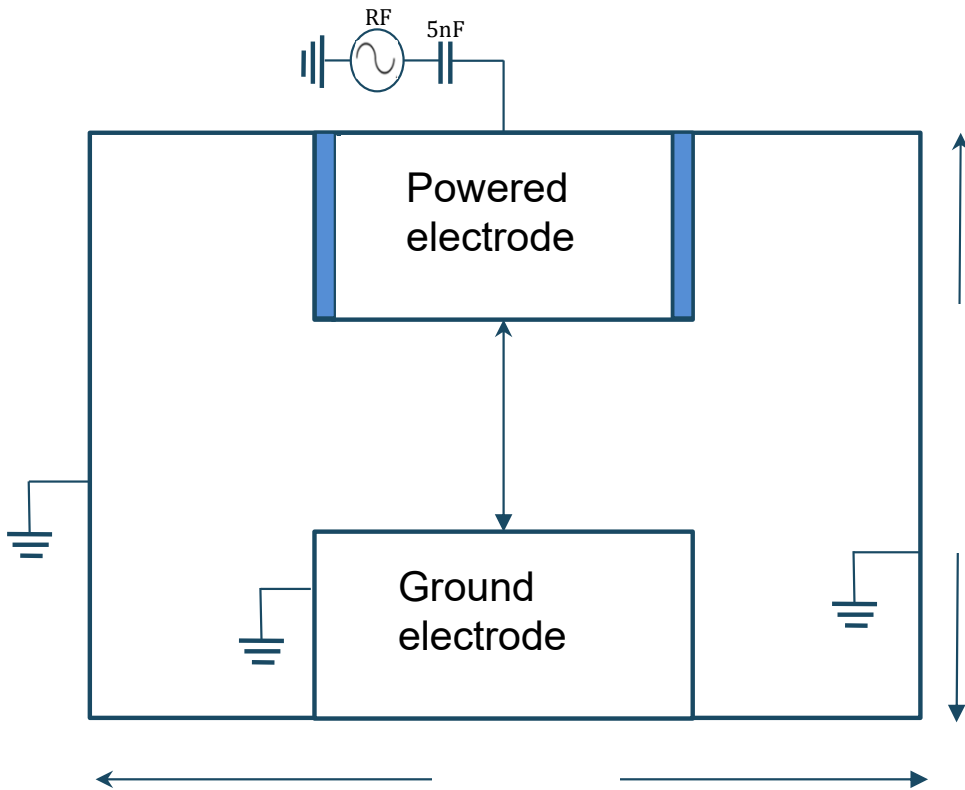
Digital twin framework : optimization + HPC

Fluid-based approaches cannot capture IAEDF
First-principles Particle-in-cell required



github.com/optimas-org/optimas

Plasma reactor set-up for kinetic simulations



Experimental operating parameters**

Powered RF Voltage : 100V; $f = 13.56$ Hz
Background pressure : 100mTorr

Kinetic simulation parameters

Grid : 256 X 128
Simulation time : 5000 RF cycles
Timestep (dt) : $(1/400 f)$

Initialized with ~ 1 Million particles

At the end 7.4 M particles

Monte Carlo Collisions for Argon chemistry

electrons : elastic, excitation, ionization

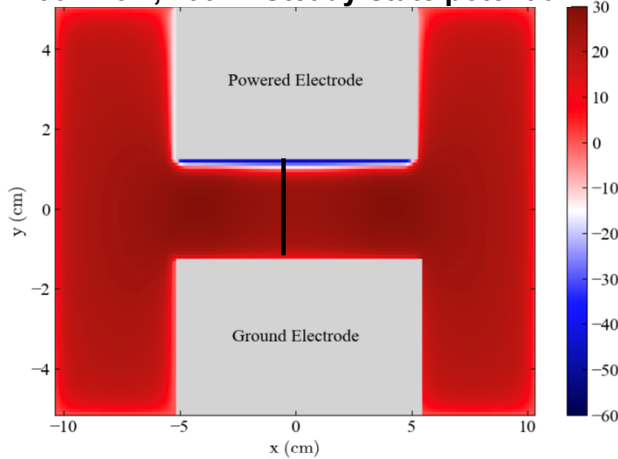
Ions: elastic, back-scattering

*Shahid Rauf, On uniformity and non-local transport in low-pressure CCP, PSST, 2020

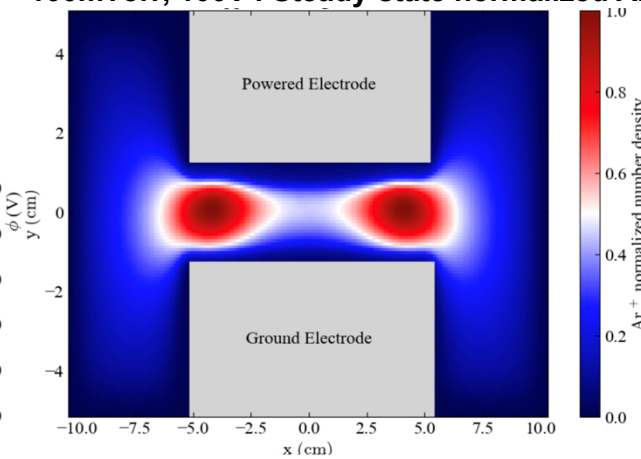
**P.J. Hargis et al., The GEC RF reference cell: A defined parallel plate RF system for expt and theoretical studies of plasma discharge, Rev of Sc.Instr, 1994

Capturing kinetic effects at reactor scale (100mTorr, 100V)

100mTorr, 100V : Steady-state potential



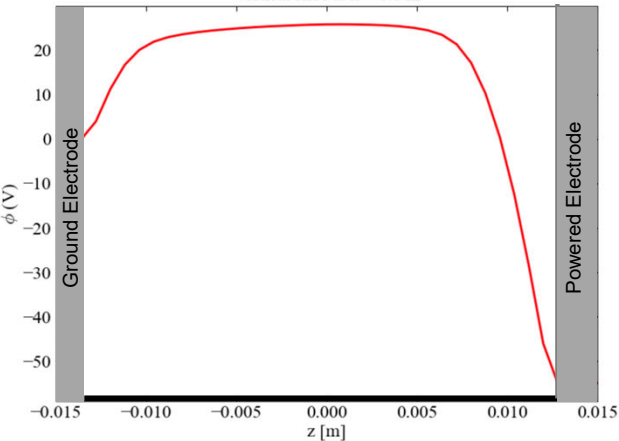
100mTorr, 100V : Steady-state normalized Ar⁺ density



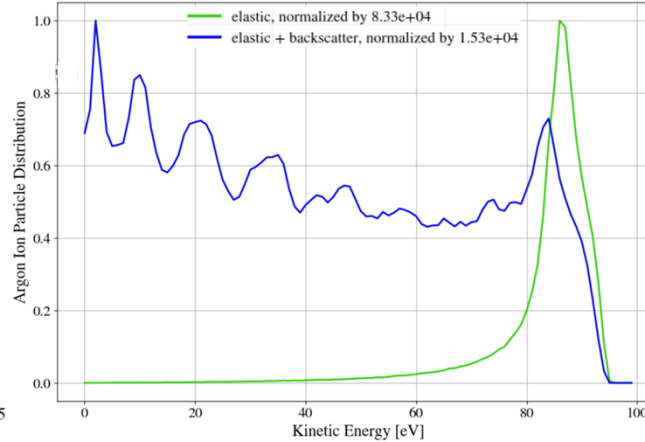
Simulations capture kinetic effects

- DC bias voltage builds at powered electrode due to external circuit with capacitor
- Steady-state within 1000 RF cycles ($73\mu\text{s}$)
- IEDF peak \sim voltage drop at powered electrode for case with elastic collisions only
- Back-scattering damps high-energy and leads to resonant peaks
- Simulations were performed for 3000 RF cycles (0.2 ms) and required 17 hours of walltime

Vertical slice at $x = 0.0$ m

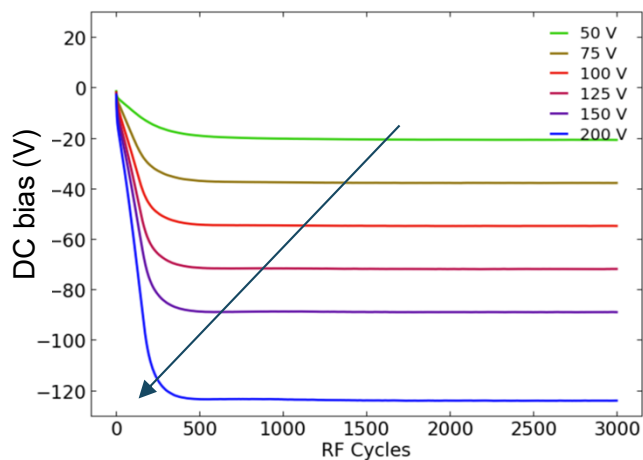


IEDF on Powered Electrode

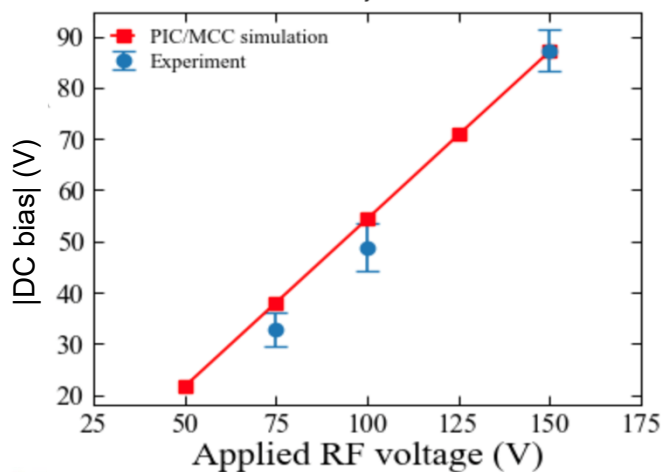
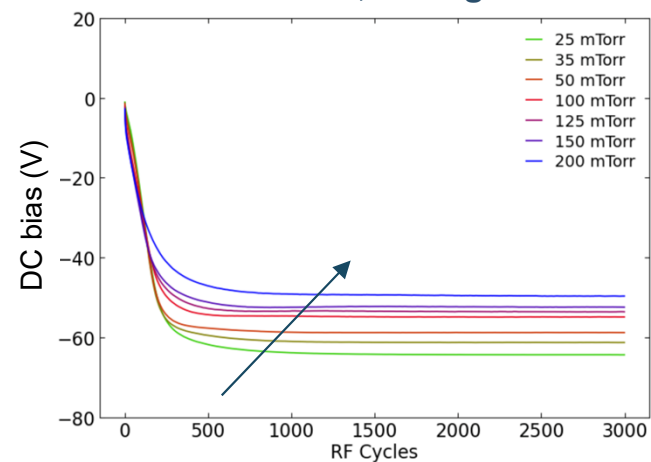


Simulated results agree with experiments

Voltage Scan, Pressure=100mTorr



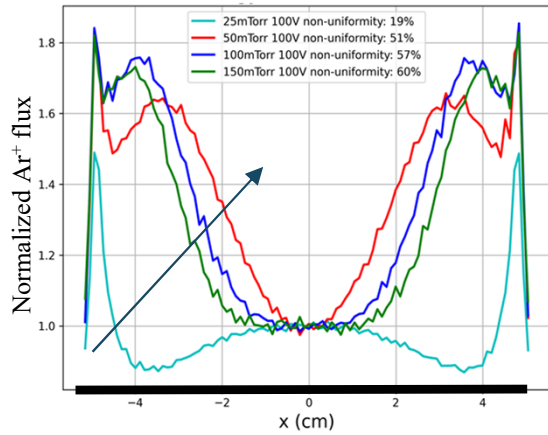
Pressure Scan, Voltage=100V



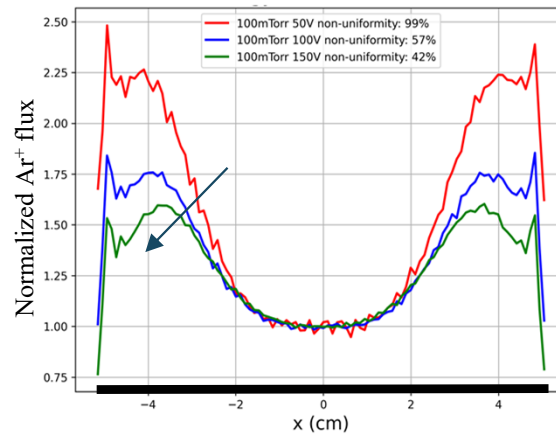
- Increase in V – *increases* DC bias
- Increase in P – *decreases* DC bias
- Simulated DC bias agrees with experimental measurements*

Identifying optimum parameters for etch uniformity

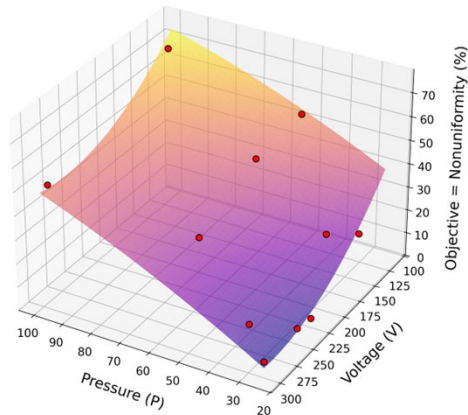
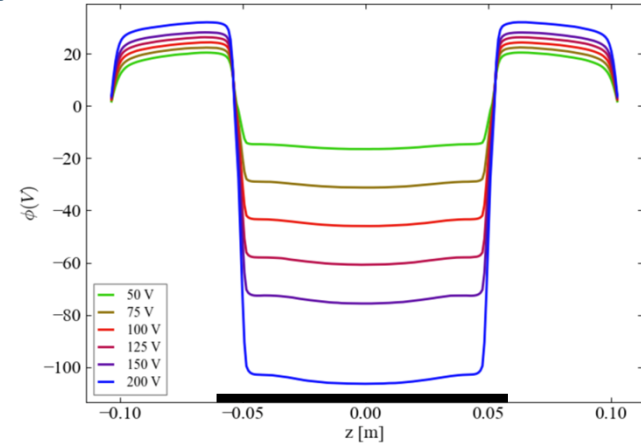
Higher P : *increases* Ar⁺ flux non-uniformity



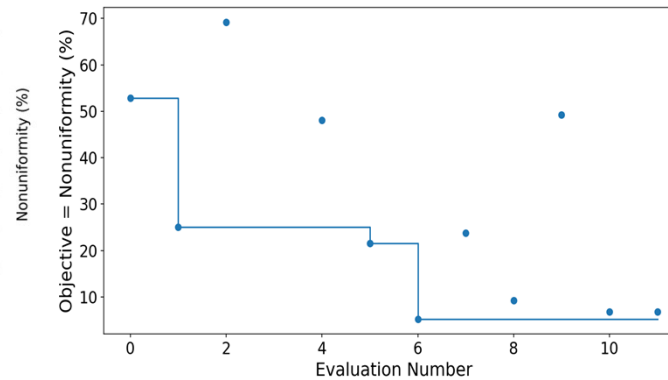
Higher V : *decreases* Ar⁺ flux non-uniformity



Electric potential along powered electrode



Optimization History



ML-enhanced Bayesian optimization (BO) studies

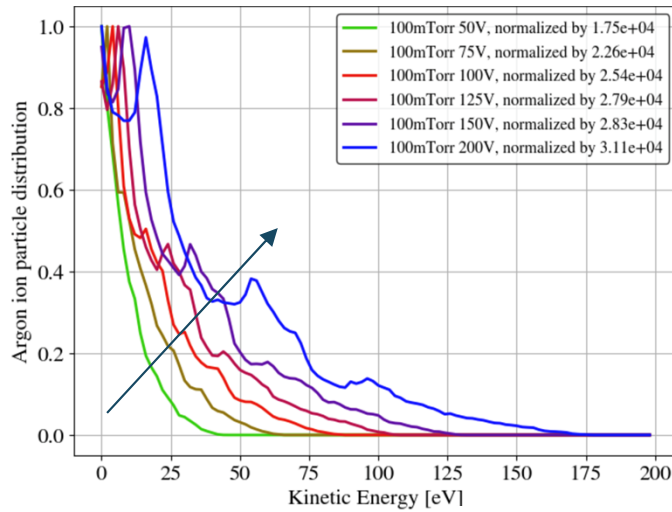
Parameter space : P (25-200 mTorr) ; V (50-300 V)

Optimum value is 25mTorr, 300V

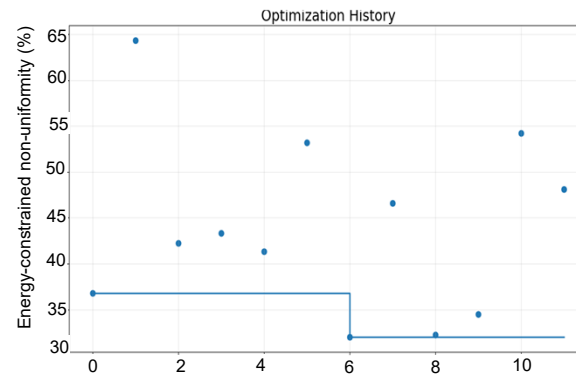
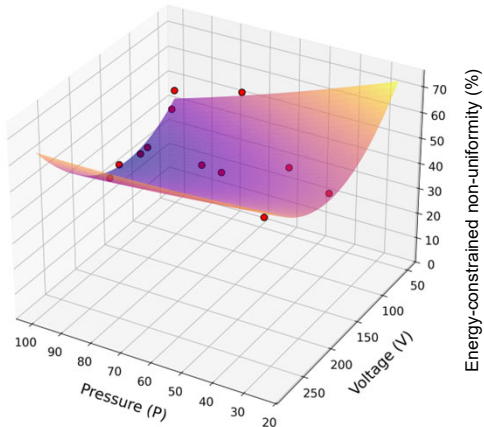
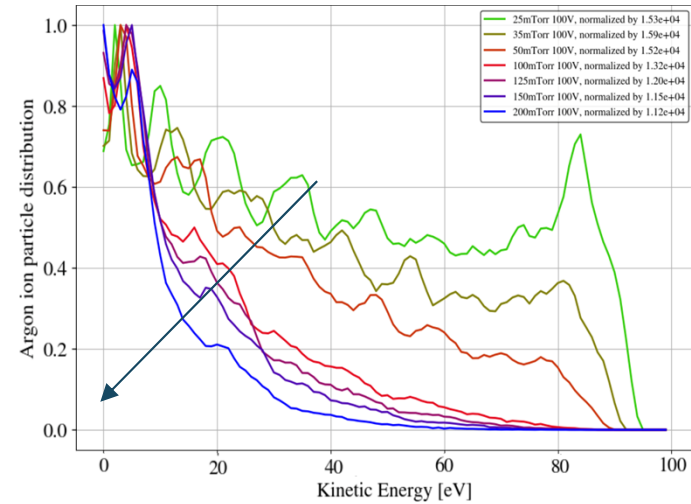
12 evaluations using GPU-accelerated HPC simulations required to achieve convergence

Energy-constrained uniformity optimization

Effect of voltage on IEDF on powered electrode

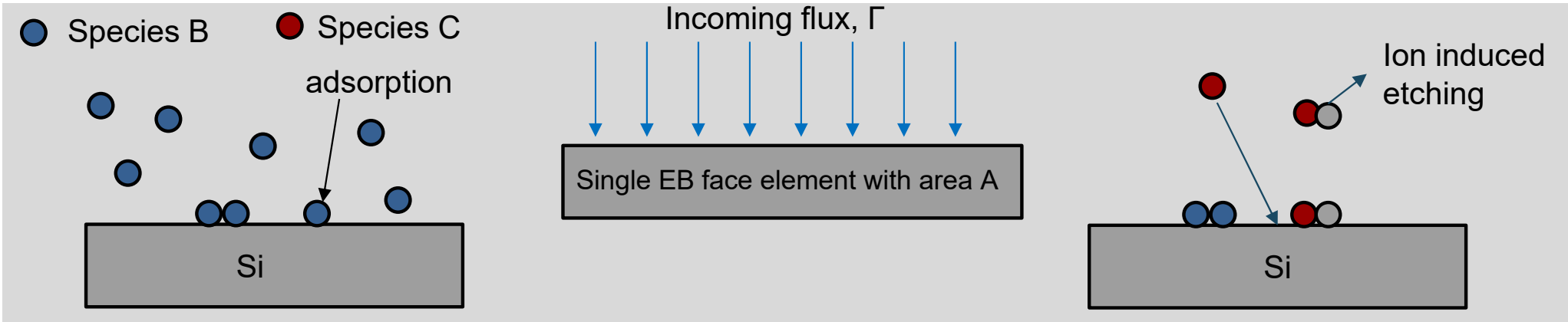


Effect of pressure on IEDF on powered electrode

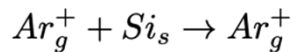
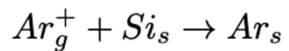


- Ion energies affect etch quality and precision.
- Low pressure, high voltage maximize uniformity – but ion energies are high
- **Uniformity with energy constraints** is important for fabrication

New surface physics module to capture etch evolution



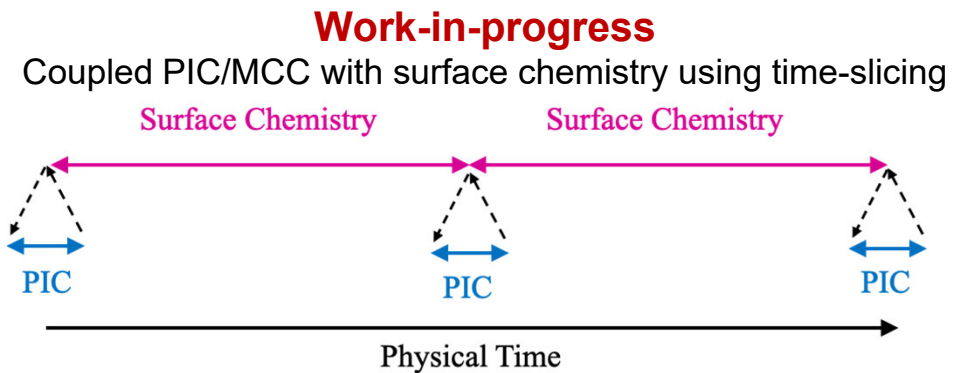
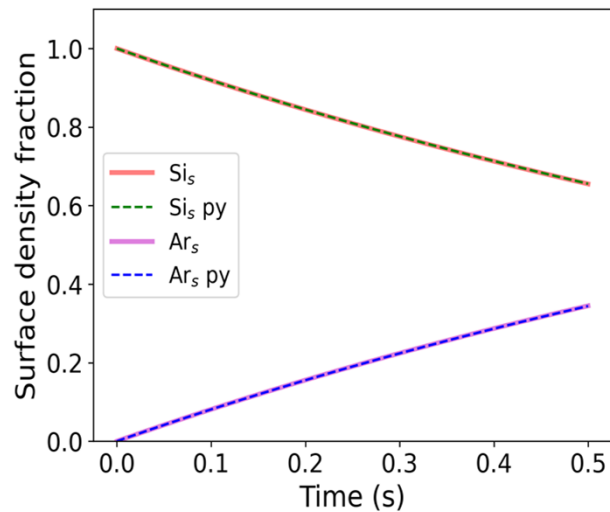
Reactions:
Adsorption and Desorption



Inputs:

$$Ar_g^+ \text{ Influx} = 10^{19} \text{ m}^{-2}\text{s}^{-1}$$

$$Ar_g^+ E_{in} = 40\text{eV}$$



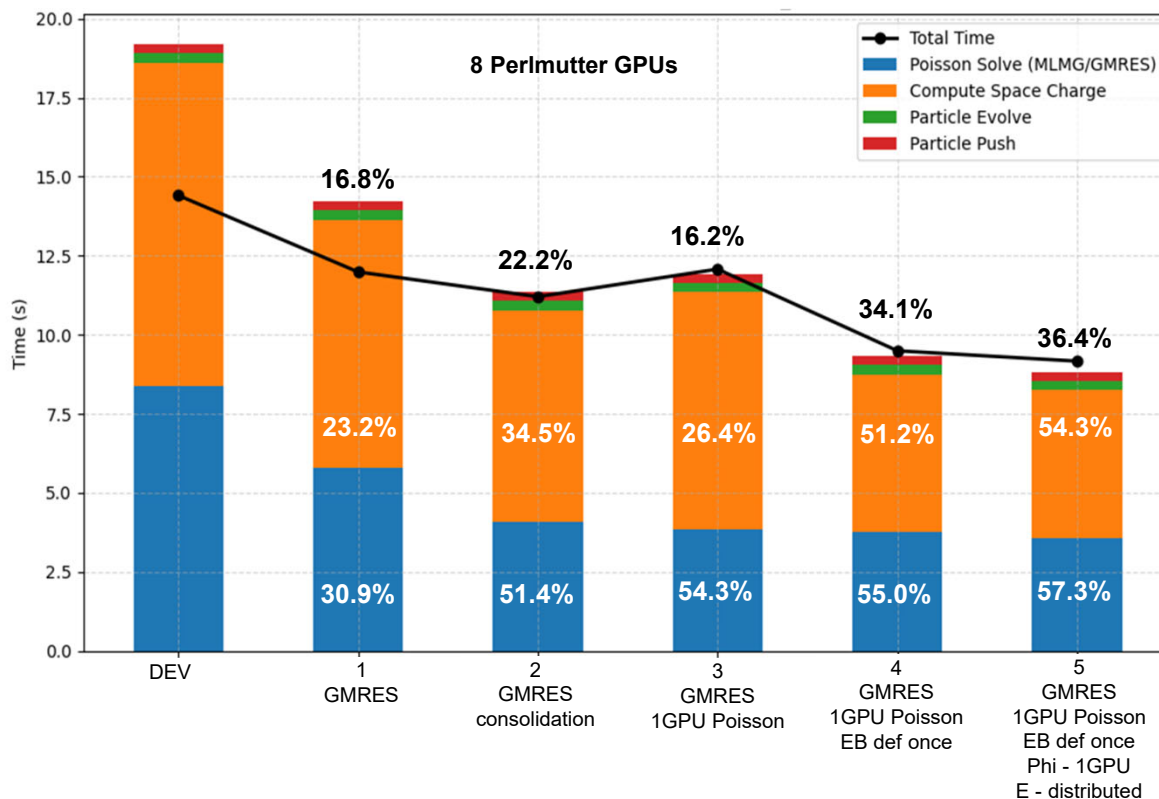
Algorithmic improvements for computational efficiency

Step-by-step improvements:

1. GMRES instead of MLMG for Poisson solve
2. Consolidation/agglomeration in GMRES cycle
3. GMRES + Poisson on 1 GPU (potential + E), communicate potential, Ex, Ey, Ez
4. Remove duplicate definition for EB for Poisson solve
5. Poisson on 1GPU, communicate potential, E on distributed GPU

Achieved ~37% speed-up > proposed speedup of 20%

Our solution : Poisson solve on reduced GPUs than particle methods – is broadly applicable for other electrostatic applications



Partnerships : National Lab, University, Industry



Dr. Ricardo Ruiz, Director,
[CHiPPS](#), LBNL



Synergistic Activities:

Received Molecular Foundry User-Proposal award to perform plasma etch experiments using inductively coupled plasma reactor and compare with plasma-surface chemistry enabled PIC/MCC simulations

Dr. Sergey Averkin,
TEL Technology Center,
America, LLC



Awarded a new HPC4EI project in partnership with TEL Technology Center, for high-frequency plasma reactor studies.

Interest in work from researchers from **Applied Materials** and **LAM Research**, who may also benefit from the open-source, industry compatible BSD-3-Clause-LBNL licensing of our codes and workflows.

Alignment with DOE's Genesis Mission

Genesis Mission

National Science and Technology Challenge : Recentering Microelectronics in America

“An AI-driven full-stack co-design ecosystem will enable faster innovation cycles, de-risk ultra-efficient manufacturing processes and component design”

Our digital twin framework with ML-enhanced Bayesian optimization workflow with accurate kinetic modeling will enable process design and optimization

- accelerating lab-to-fab time
- reducing costly trial-and-error experiments (costly substrates, and energy-use)
- reducing discard-rate, increasing yield with high-precision etch
- boosting global competitiveness of chip manufacturing

It can fit into a larger workflow, where experimental measurements are also used to train models

Workforce development for microelectronics

- July 7 - July 11, 2025
- 21 high school students from the Berkeley Lab Director's Apprenticeship Program / Interdisciplinary Pathways to Machine Learning and Data Science participated
- 10 LBNL researchers + 2 external researchers gave talks, led tours, or were part of the career panel

Faith Dukes
Task Lead



Alisa Betalle
Co-Lead



Corbin Shatto
Co-Lead

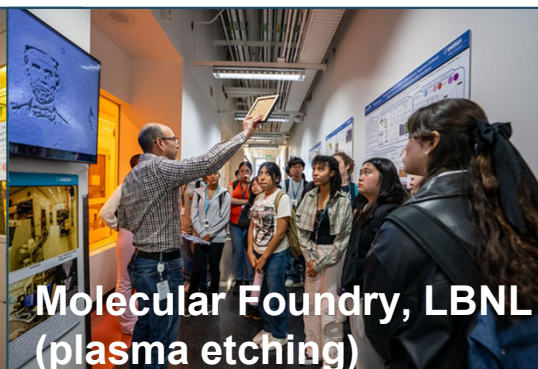
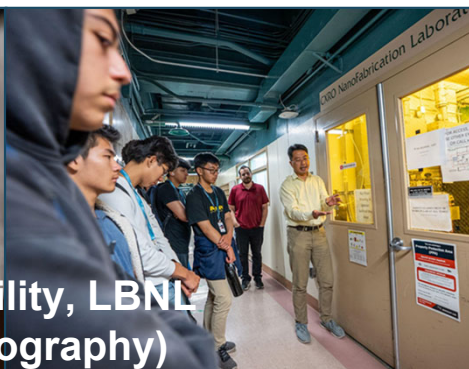
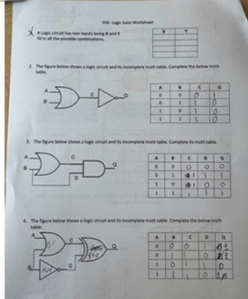
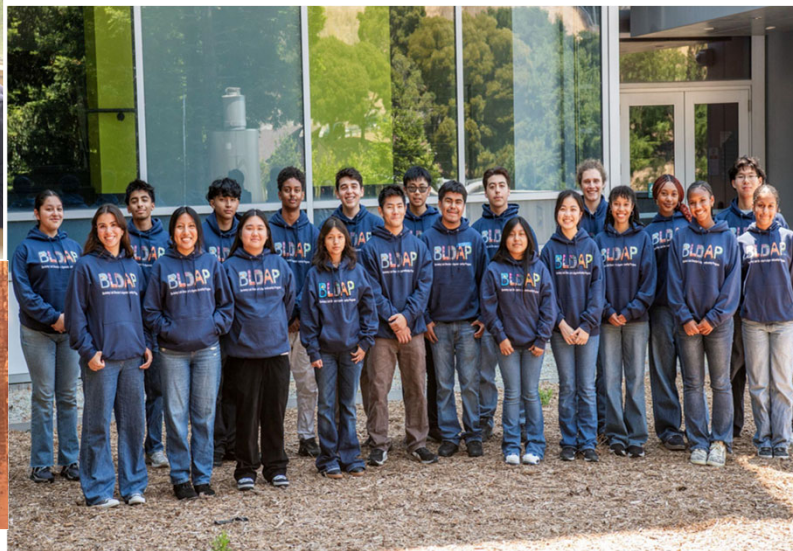
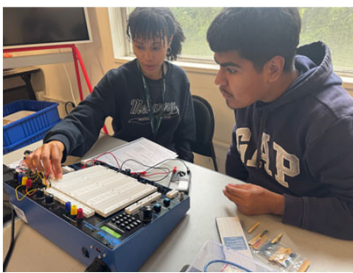


Revathi
Participant



Monday	Tuesday	Wednesday	Thursday	Friday
<p>Introduction</p> <p>Relevance of microelectronics</p> <p>Evolution of microelectronics over the years</p>	<p>Modeling & Simulation of plasma reactor for etching - python scripting to visualize results</p> <p>Design and Materials Talk</p> <p>Device Materials Talk</p>	<p>Lithography Lab / Circuit Design Trainer Lab</p> <p>Center for X-Ray Optics Tour (Microelectronics patterning)</p>	<p>Lithography Lab / Circuit Design Trainer Lab</p> <p>Molecular Foundry Tour (Reactive ion etch devices for chip fabrication)</p> <p>Nanofabrication Facility Tour</p>	<p>Chips and System Modeling Talk</p> <p>National Energy Research Scientific Computing Center (NERSC) Tour</p> <p>Career Talk (public and viewed by other summer interns at Berkeley Lab) ~ 120 students</p>

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Thanks to the team and funding acknowledgement

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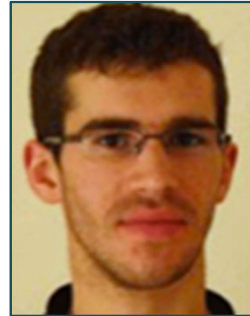
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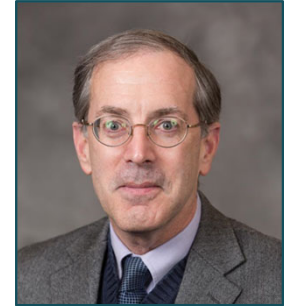
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Mark Kushner, (advisor)
William P Allis Distinguished
Professor, U. of Michigan



Andrea Diaz
St. Mary's University
SULI Intern at LBNL



Jorge Quiroga
Graduate student
NMT University



Tristan Jiron
Undergrad
NMT University



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**Thank you !
Questions and comments
are welcome**